

The eGaN® FET  
Journey Continues



Thermal Model of EPC2053

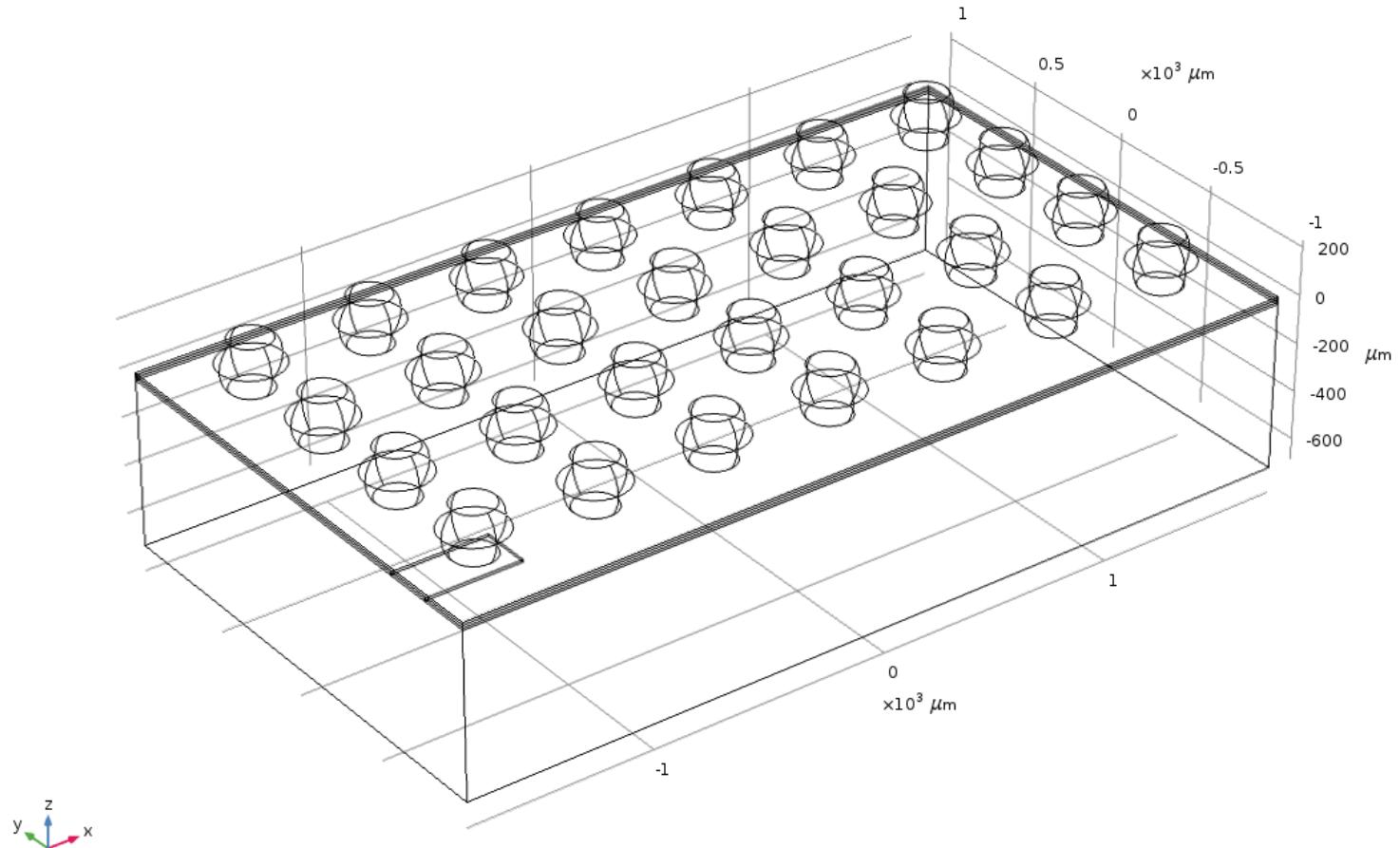
*Efficient Power Conversion Corporation*

# EPC2053 FEA thermal simulation



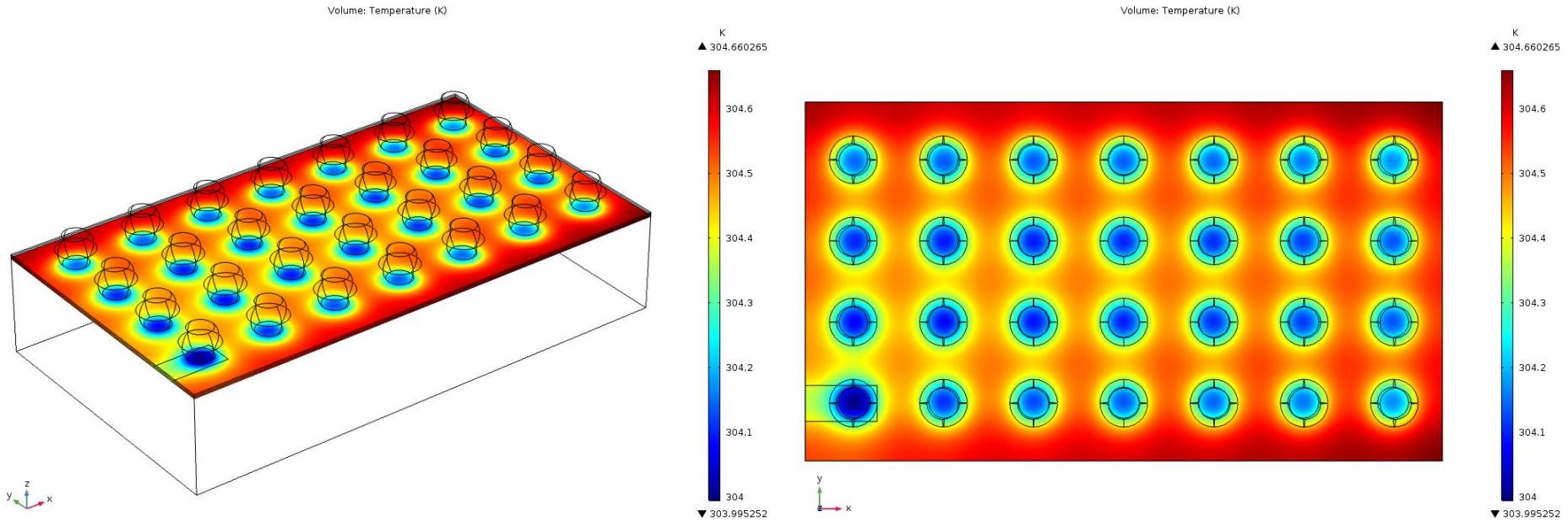
- The thermal model applies to EPC2053.
- A power dissipation of 1 W in the device active area is assumed.
- Finite element analysis (FEA) thermal simulations
  - $R_{\Theta_{JB}}$  and  $R_{\Theta_{JC}}$  are obtained by stationary simulations.
  - $Z_{\Theta_{JB}}$  and  $Z_{\Theta_{JC}}$  are obtained by transient simulations.
- R-C thermal model is generated.

# EPC2053 device structure



# Steady-state $R_{\Theta JB}$

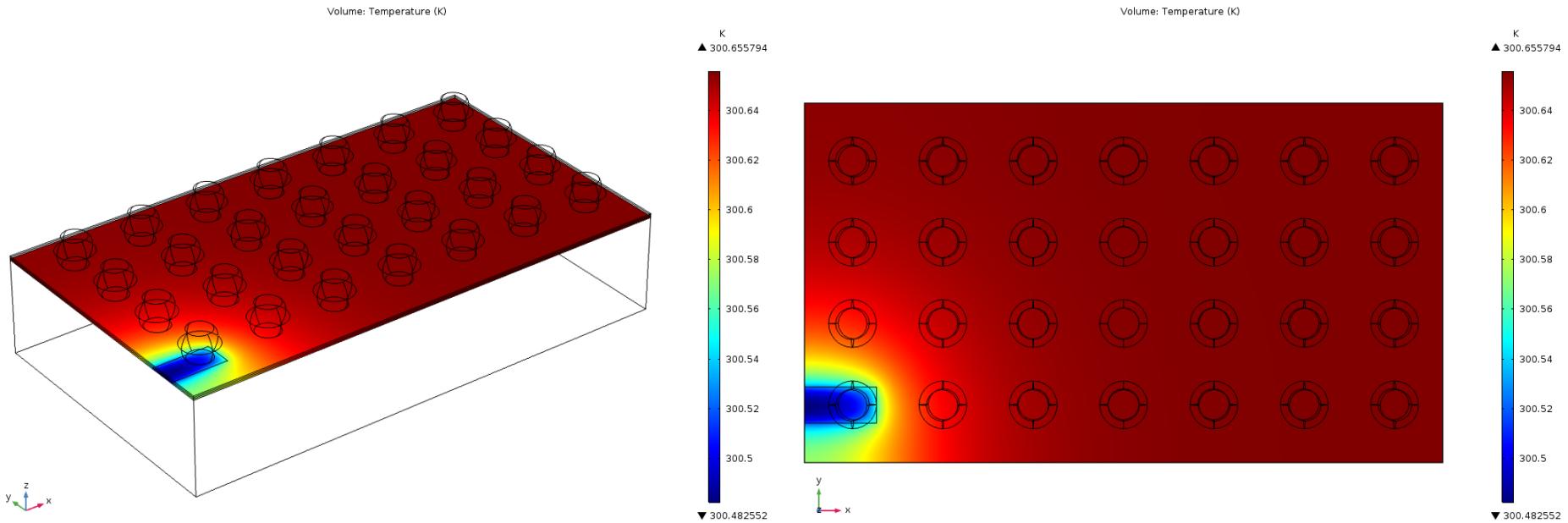
**Typical  $R_{\Theta JB} = 4.7 \text{ }^{\circ}\text{C/W}$**



- Operating condition: Power = 1 W in the active area.
- Boundary condition: Temperature of top of solder bars set to be 300 K.

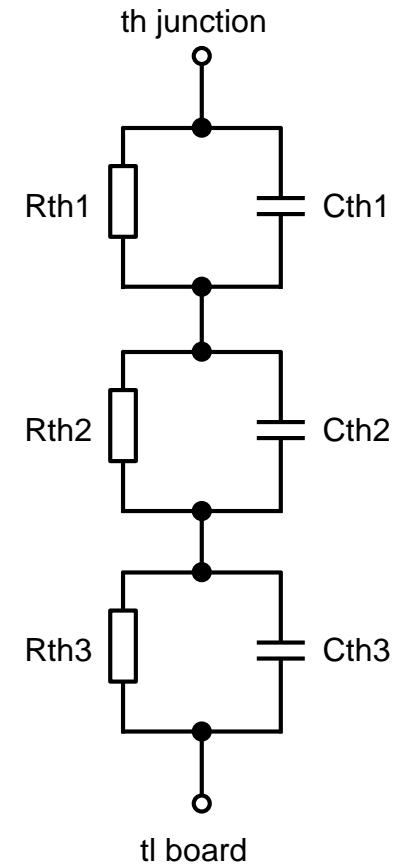
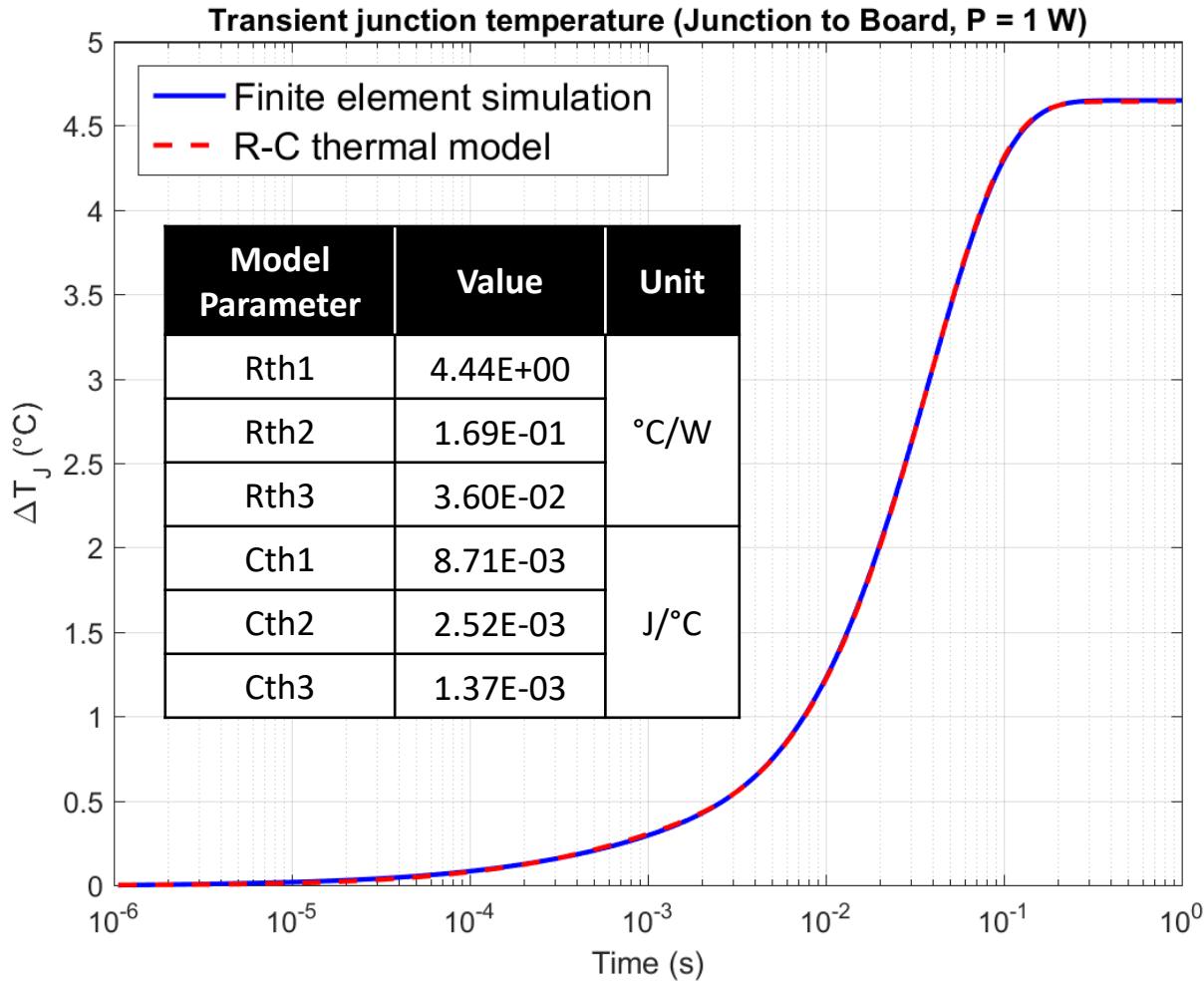
# Steady-state $R_{\Theta JC}$

**Typical  $R_{\Theta JC} = 0.7 \text{ }^{\circ}\text{C/W}$**

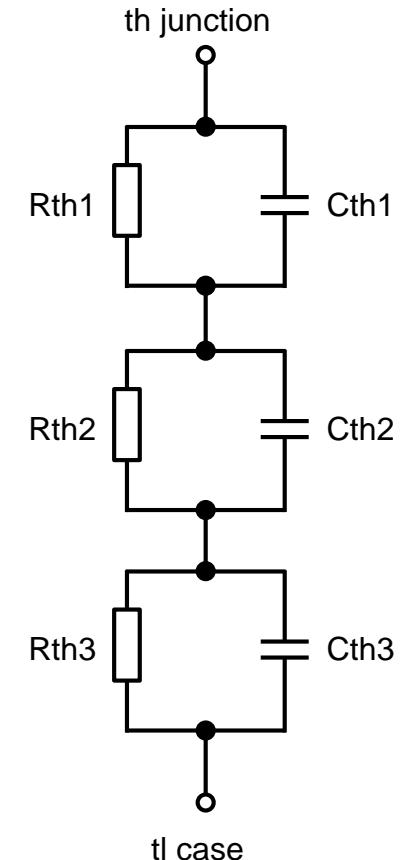
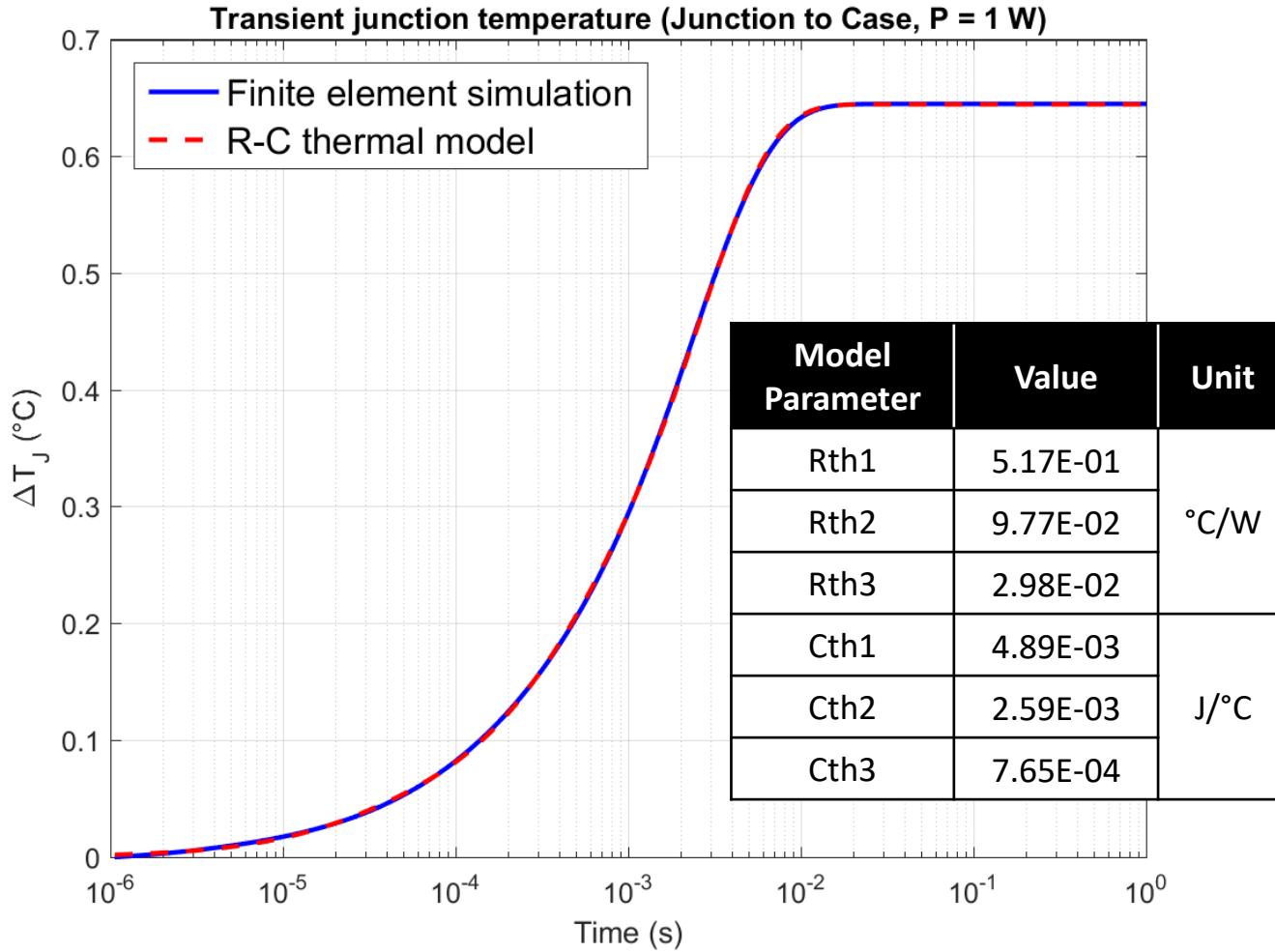


- Operating condition: Power = 1 W in the active area.
- Boundary condition: Temperature of bottom of the device backside set to be 300 K.

# $Z_{\Theta JB}$ R-C thermal model



# $Z_{\Theta JC}$ R-C thermal model





*The end of the  
road for silicon...  
  
but a clear road  
ahead for GaN  
FETs and ICs!*

